CSIR - NATIONAL PHYSICAL LABORATORY

Dr. K. S. Krishnan Marg, New Delhi – 110012 (INDIA)

Contact: 011-4560-8645

011-4560-8624

Email: sr.cosp@nplindia.org

purchase-sol@nplindia.org

From: Director, CSIR-NPL

No. 14-VI/HM(1120)23PB/T-131

Dated: 21.11.2023

CORRIGENDUM

With reference to NPL's Global Tender ID: 2023_CSIR_732576_1 for "Resistance Thermometry Bridge and Accessories". Following extension in due date of submission & date of opening of the said tender may be read exactly as follows:

Due date & time of tender submission

For : 28.11.2023 up to 3:00 PM (IST) Read as: 05.12.2023 up to 3:00 PM (IST)

Date & Time of Tender Opening

For : 29.11.2023 at 3:00 PM (IST) Read as: 06.12.2023 at 3:00 PM (IST)

All other terms & conditions of said tender will remain the same.

Sr. Controller of Stores & Purchase

Minutes of the Meeting (MOM) of the Pre-Bid Conference

Date: 07/11/2023

With reference to the File No. 14-VI/HM (1120)23/PB dated 15.04.2023, regarding Pre-Bid conference for procurement of "Resistance Thermometry Bridge and Accessories", a Pre-Bid Conference was held on 07/11/2023 (Tuesday) at 04.00 PM in the Second Floor Conference Room, Main Building CSIR-NPL, New Delhi under Chairmanship of Dr. H. K. Singh.

Following vendors & their representatives participated in Pre-Bid Conference.

1. Mr. Ritesh Tiwari from M/s Wika Instruments India Pvt. Ltd., Plot No. 40 & 54, Gat No. 94+100, Hi-Cliff Industrial Estate, Village Kesnand, Wagholi, Pune - 412 207. Maharashtra, India,

2. M/s Measurements International LLP, 410, 4th Floor, K M Trade Tower, Radisson Holtel Building, Sector-14, Kaushambi, Ghaziabad, Uttar Pradesh – 201010 (Physically not Present, Agreement submitted By Email)

The following members attended the meeting:

1.	Dr. H. K. Singh, Chief Scientist	Chairman
2.	Dr. Sachchidanand Singh, Chief Scientist	Member
3.	Dr. S. P. Khanna, Senior Principal Scientist	Member
4.	Dr. P. K. Siwach, Principal Scientist	Expert
5.	Dr. Priyanka Jain, Senior Principal Scientist	Expert
6.	Dr. Hansraj Meena, STO-1	Indenter
7.	Dr. D. D. Shivagan, Senior Principal Scientist	Member

Mr. Hansraj Meena, presented the tendered specifications to the pre-bid participants.

Each and every point of technical specifications and all mandatory documents and form with tender was discussed in details by the committee members. The queries received from vendor during the pre-bid meeting were discussed and clarified.

The responses received from vendors on the technical specifications are attached as Annexure -I

The detail final specifications are given in Annexure -II

The meeting ended with thanks to Dr. Sachchidanand Singh.

Opening: 150mm X 150mm or Higher Silicon Oil: Will be supplied with bath

Connecting Cable for Reference Resistors

Connecting Cable and adaptor box for SPRT connection (2 Nos)

Resistance Thermometry Bridge and Accessories Specification Ratio Range: 0 to 1.299999999 or Higher Ratio Accuracy: ≤ ± 20ppb (± 5 µK) over full range Resolution: 1 ppb (0.25µK) Sensing Current: (1mA, 2mA, 5mA) X 0.1,10 and $\sqrt{2}$ Sensing Current Accuracy: ±0.1% Band width: (0.5, 0.2, 0.1) Hz X 0.1 and 0.001 Measuring Range: 0 to 260 Ω or Higher Rated Accuracy Range: 0 to 130 Ω $R_{s \text{ Range}}$: 1 to 200 Ω Communication: IEEE-488.2/RS-232 along with Data Acquisition System and Software Power: 240 V/50Hz/60Hz Multi Channel Scanner with Pre -Heat (10 Channel or More) Resistance value: 1 Ω Tolerance: ±10 ppm Long-term stability: 0.5 ppm per year Temperature Coefficient: 0.5 ppm per °C Resistance value: 10 Ω Tolerance: ±10 ppm Long-term stability: 0.5 ppm per year Temperature Coefficient: 0.5 ppm per °C Resistance value: 25Ω Tolerance: ±10 ppm Long-term stability: 0.5 ppm per year Temperature Coefficient: 0.5 ppm per °C Resistance value: 100Ω Tolerance: ±10 ppm Long-term stability: 0.5 ppm per year Temperature Coefficient: 0.5 ppm per °C Maintenance Bath for Standard Resistance: Temperature Range: 5 °C to 50 °C Stability: ± 0.010°C Immersion Depth: 200mm or Higher

(4 Nos)

Calibration Certificate of the Bridge and Standard Resistances as per ISO IEC 17025:2017